Notice of References Cited	Application/Control No. 10/561,680	Applicant(s)/Patent Under Reexamination OHNO ET AL.		
	Examiner	Art Unit	Page 1 of 1	
	KARUNA P. REDDY	1796		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,964,999 B1	11-2005	Nakagawa et al.	525/193
	В	US-			
	U	US-			
	ם	US-			
	ш	US-			
	F	US-			
	O	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 9943719 A1	09-1999	World Intellect	NAKAGAWA et al.	C08F 08/14
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.